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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

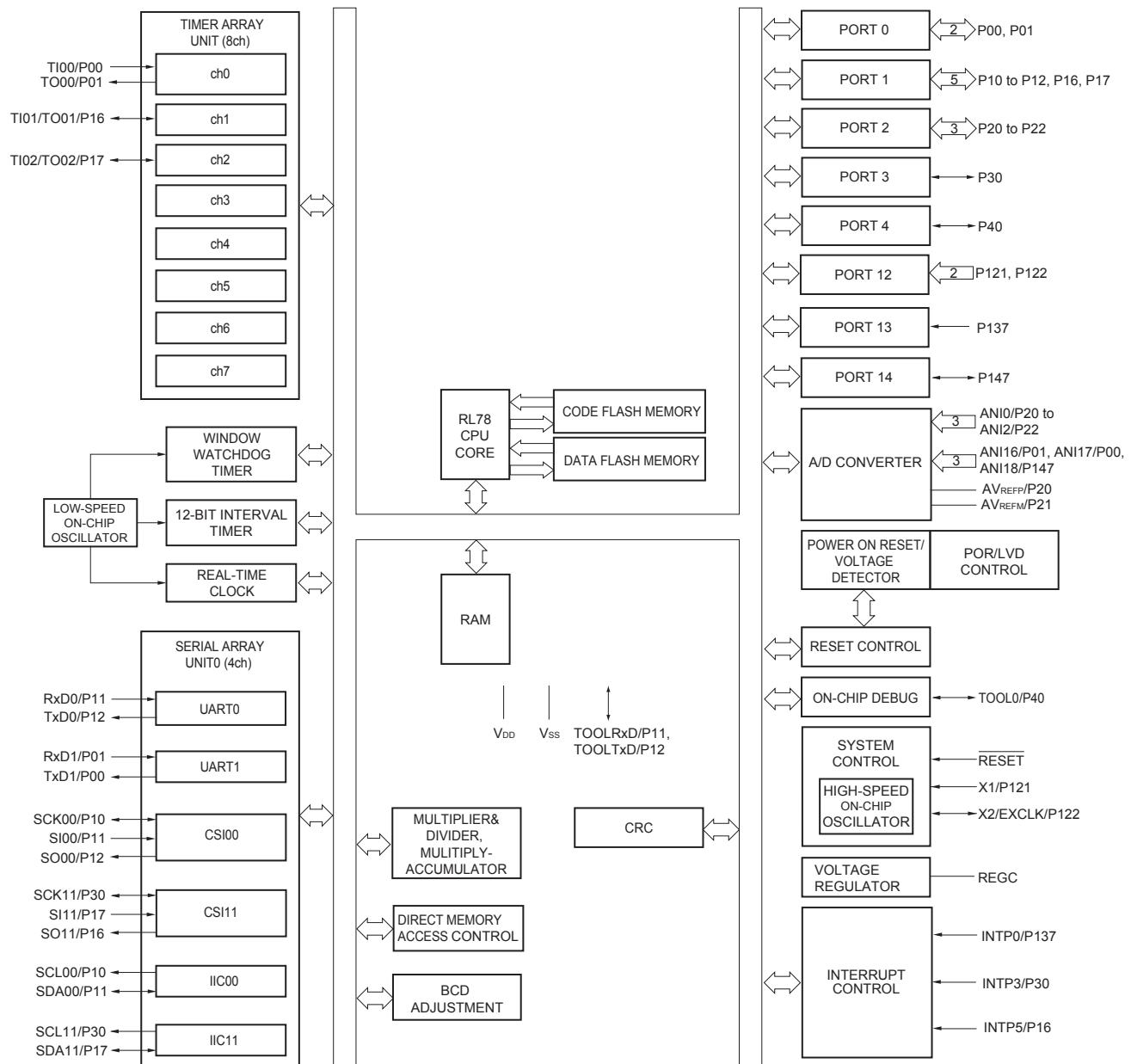
Applications of "[Embedded - Microcontrollers](#)"

Details

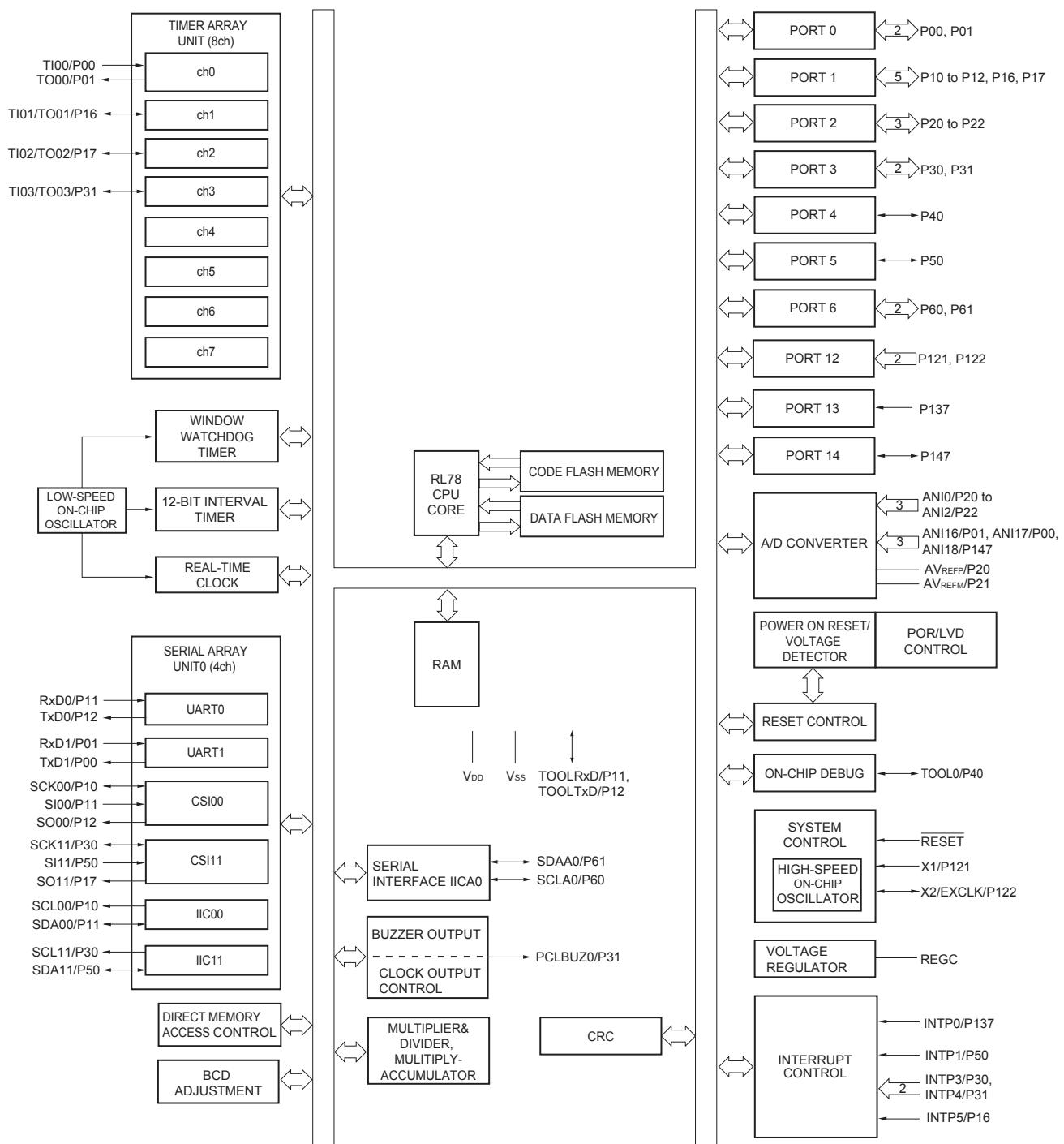
Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I ² C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	48
Program Memory Size	96KB (96K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 12x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LFQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f100lfafb-30

1.5 Block Diagram

1.5.1 20-pin products



1.5.2 24-pin products



Notes 1. Total current flowing into V_{DD} , EV_{DD0} , and EV_{DD1} , including the input leakage current flowing when the level of the input pin is fixed to V_{DD} , EV_{DD0} , and EV_{DD1} , or V_{SS} , EV_{SS0} , and EV_{SS1} . The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

2. When high-speed on-chip oscillator and subsystem clock are stopped.
3. When high-speed system clock and subsystem clock are stopped.
4. When high-speed on-chip oscillator and high-speed system clock are stopped. When $AMPHS1 = 1$ (Ultra-low power consumption oscillation). However, not including the current flowing into the 12-bit interval timer and watchdog timer.
5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 32 MHz

$2.4 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 16 MHz

LS (low-speed main) mode: $1.8 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 8 MHz

LV (low-voltage main) mode: $1.6 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 4 MHz

- Remarks**
1. f_{MX} : High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 2. f_{IH} : High-speed on-chip oscillator clock frequency
 3. f_{SUB} : Subsystem clock frequency (XT1 clock oscillation frequency)
 4. Except subsystem clock operation, temperature condition of the TYP. value is $T_A = 25^\circ\text{C}$

- Notes**
1. Total current flowing into V_{DD} , EV_{DD0} , and EV_{DD1} , including the input leakage current flowing when the level of the input pin is fixed to V_{DD} , EV_{DD0} , and EV_{DD1} , or V_{SS} , EV_{SS0} , and EV_{SS1} . The values below the MAX. column include the peripheral operation current . However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
 2. During HALT instruction execution by flash memory.
 3. When high-speed on-chip oscillator and subsystem clock are stopped.
 4. When high-speed system clock and subsystem clock are stopped.
 5. When high-speed on-chip oscillator and high-speed system clock are stopped. When $RTCLPC = 1$ and setting ultra-low current consumption ($AMPHS1 = 1$). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode:	$2.7 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 32 MHz
	$2.4 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 16 MHz
LS (low-speed main) mode:	$1.8 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 8 MHz
	LV (low-voltage main) mode: $1.6 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}$ @ 1 MHz to 4 MHz
 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.

- Remarks**
1. f_{MX} : High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 2. f_{IH} : High-speed on-chip oscillator clock frequency
 3. f_{SUB} : Subsystem clock frequency (XT1 clock oscillation frequency)
 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is $T_A = 25^\circ\text{C}$

6. Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2} and I_{ADC} when the A/D converter operates in an operation mode or the HALT mode.
7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of I_{DD1} , I_{DD2} or I_{DD3} and I_{LVD} when the LVD circuit is in operation.
8. Current flowing only during data flash rewrite.
9. Current flowing only during self programming.
10. For shift time to the SNOOZE mode, see **18.3.3 SNOOZE mode**.

Remarks

- 1. f_{IL} : Low-speed on-chip oscillator clock frequency
- 2. f_{SUB} : Subsystem clock frequency (XT1 clock oscillation frequency)
- 3. f_{CLK} : CPU/peripheral hardware clock frequency
- 4. Temperature condition of the TYP. value is $T_A = 25^\circ\text{C}$

(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)

 $(T_A = -40$ to $+85^\circ\text{C}$, $1.6 \text{ V} \leq EV_{DD0} = EV_{DD1} \leq V_{DD} \leq 5.5 \text{ V}$, $V_{SS} = EV_{SS0} = EV_{SS1} = 0 \text{ V}$)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		LV (low-voltage main) Mode		Unit	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
SCKp cycle time	t _{KCY1}	$t_{KCY1} \geq 4/f_{CLK}$	2.7 V $\leq EV_{DD0} \leq 5.5$ V	125		500		1000		ns
			2.4 V $\leq EV_{DD0} \leq 5.5$ V	250		500		1000		ns
			1.8 V $\leq EV_{DD0} \leq 5.5$ V	500		500		1000		ns
			1.7 V $\leq EV_{DD0} \leq 5.5$ V	1000		1000		1000		ns
			1.6 V $\leq EV_{DD0} \leq 5.5$ V	—		1000		1000		ns
SCKp high-/low-level width	t _{Kh1} , t _{kl1}	4.0 V $\leq EV_{DD0} \leq 5.5$ V	t _{KCY1} /2 – 12		t _{KCY1} /2 – 50		t _{KCY1} /2 – 50		ns	
		2.7 V $\leq EV_{DD0} \leq 5.5$ V	t _{KCY1} /2 – 18		t _{KCY1} /2 – 50		t _{KCY1} /2 – 50		ns	
		2.4 V $\leq EV_{DD0} \leq 5.5$ V	t _{KCY1} /2 – 38		t _{KCY1} /2 – 50		t _{KCY1} /2 – 50		ns	
		1.8 V $\leq EV_{DD0} \leq 5.5$ V	t _{KCY1} /2 – 50		t _{KCY1} /2 – 50		t _{KCY1} /2 – 50		ns	
		1.7 V $\leq EV_{DD0} \leq 5.5$ V	t _{KCY1} /2 – 100		t _{KCY1} /2 – 100		t _{KCY1} /2 – 100		ns	
		1.6 V $\leq EV_{DD0} \leq 5.5$ V	—		t _{KCY1} /2 – 100		t _{KCY1} /2 – 100		ns	
Slp setup time (to SCKp↑) <small>Note 1</small>	t _{SIK1}	4.0 V $\leq EV_{DD0} \leq 5.5$ V	44		110		110		ns	
		2.7 V $\leq EV_{DD0} \leq 5.5$ V	44		110		110		ns	
		2.4 V $\leq EV_{DD0} \leq 5.5$ V	75		110		110		ns	
		1.8 V $\leq EV_{DD0} \leq 5.5$ V	110		110		110		ns	
		1.7 V $\leq EV_{DD0} \leq 5.5$ V	220		220		220		ns	
		1.6 V $\leq EV_{DD0} \leq 5.5$ V	—		220		220		ns	
Slp hold time (from SCKp↑) <small>Note 2</small>	t _{ksi1}	1.7 V $\leq EV_{DD0} \leq 5.5$ V	19		19		19		ns	
		1.6 V $\leq EV_{DD0} \leq 5.5$ V	—		19		19		ns	
Delay time from SCKp↓ to SOp output <small>Note 3</small>	t _{ks01}	1.7 V $\leq EV_{DD0} \leq 5.5$ V C = 30 pF ^{Note 4}		25		25		25	ns	
		1.6 V $\leq EV_{DD0} \leq 5.5$ V C = 30 pF ^{Note 4}		—		25		25	ns	

- Notes**
- When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp setup time becomes “to SCKp↓” when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes “from SCKp↓” when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes “from SCKp↑” when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the Slp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

(7) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only) (2/2)

($T_A = -40$ to $+85^\circ\text{C}$, $2.7 \text{ V} \leq EV_{DD0} = EV_{DD1} \leq V_{DD} \leq 5.5 \text{ V}$, $V_{SS} = EV_{SS0} = EV_{SS1} = 0 \text{ V}$)

Parameter	Symbol	Conditions	HS (high-speed main) Mode	LS (low-speed main) Mode	LV (low-voltage main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Slp setup time (to SCKp \downarrow) ^{Note 2}	tsIK1	4.0 V \leq EV _{DD0} \leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, C _b = 20 pF, R _b = 1.4 k Ω	23		110		ns
		2.7 V \leq EV _{DD0} < 4.0 V, 2.3 V \leq V _b \leq 2.7 V, C _b = 20 pF, R _b = 2.7 k Ω	33		110		ns
Slp hold time (from SCKp \downarrow) ^{Note 2}	tKSI1	4.0 V \leq EV _{DD0} \leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, C _b = 20 pF, R _b = 1.4 k Ω	10		10		ns
		2.7 V \leq EV _{DD0} < 4.0 V, 2.3 V \leq V _b \leq 2.7 V, C _b = 20 pF, R _b = 2.7 k Ω	10		10		ns
Delay time from SCKp \uparrow to SO _p output ^{Note 2}	tKS01	4.0 V \leq EV _{DD0} \leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, C _b = 20 pF, R _b = 1.4 k Ω		10		10	ns
		2.7 V \leq EV _{DD0} < 4.0 V, 2.3 V \leq V _b \leq 2.7 V, C _b = 20 pF, R _b = 2.7 k Ω		10		10	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the Slp pin and the N-ch open drain output (V_{DD} tolerance (When 20- to 52-pin products)/EV_{DD} tolerance (When 64- to 128-pin products)) mode for the SO_p pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remarks 1. R_b[Ω]:Communication line (SCKp, SO_p) pull-up resistance, C_b[F]: Communication line (SCKp, SO_p) load capacitance, V_b[V]: Communication line voltage

2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0),
g: PIM and POM number (g = 1)

3. f_{MCK}: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

4. This value is valid only when CSI00's peripheral I/O redirect function is not used.

2.6 Analog Characteristics

2.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel	Reference Voltage		
	Reference voltage (+) = AV_{REFP}	Reference voltage (+) = V_{DD}	Reference voltage (+) = V_{BGR}
Reference voltage (-) = AV_{REFM}	Reference voltage (-) = V_{SS}	Reference voltage (-) = AV_{REFM}	Reference voltage (-) = AV_{REFM}
ANI0 to ANI14	Refer to 2.6.1 (1).	Refer to 2.6.1 (3).	Refer to 2.6.1 (4).
ANI16 to ANI26	Refer to 2.6.1 (2).		
Internal reference voltage Temperature sensor output voltage	Refer to 2.6.1 (1).		—

(1) When reference voltage (+) = AV_{REFP} /ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV_{REFM} /ANI1 (ADREFM = 1), target pin : ANI2 to ANI14, internal reference voltage, and temperature sensor output voltage

($T_A = -40$ to $+85^\circ\text{C}$, $1.6 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$, $\text{V}_{\text{SS}} = 0 \text{ V}$, Reference voltage (+) = AV_{REFP} , Reference voltage (-) = $\text{AV}_{\text{REFM}} = 0 \text{ V}$)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Note 3}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$		1.2	± 3.5	LSB
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 4}		1.2	± 7.0	LSB
Conversion time	t _{CONV}	10-bit resolution Target pin: ANI2 to ANI14	3.6 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.125		39	μs
			2.7 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.1875		39	μs
			1.8 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
			1.6 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	57		95	μs
	t _{CONV}	10-bit resolution Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	3.6 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.375		39	μs
			2.7 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.5625		39	μs
			2.4 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error ^{Notes 1, 2}	E _{zs}	10-bit resolution $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Note 3}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 0.25	%FSR
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 4}			± 0.50	%FSR
Full-scale error ^{Notes 1, 2}	E _{fs}	10-bit resolution $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Note 3}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 0.25	%FSR
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 4}			± 0.50	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Note 3}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 2.5	LSB
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 4}			± 5.0	LSB
Differential linearity error ^{Note 1}	DLE	10-bit resolution $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Note 3}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 1.5	LSB
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 4}			± 2.0	LSB
Analog input voltage	V _{AIN}	ANI2 to ANI14		0		AV_{REFP}	V
		Internal reference voltage (2.4 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$, HS (high-speed main) mode)			V_{BGR} ^{Note 5}		V
		Temperature sensor output voltage (2.4 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$, HS (high-speed main) mode)			V_{TMPS25} ^{Note 5}		V

(Notes are listed on the next page.)

(2) When reference voltage (+) = $\text{AV}_{\text{REFP}}/\text{ANI}0$ ($\text{ADREFP}1 = 0$, $\text{ADREFP}0 = 1$), reference voltage (-) = $\text{AV}_{\text{REFM}}/\text{ANI}1$ ($\text{ADREFM} = 1$), target pin : ANI16 to ANI26

($T_A = -40$ to $+85^\circ\text{C}$, $1.6 \text{ V} \leq \text{EV}_{\text{DD}0} = \text{EV}_{\text{DD}1} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$, $1.6 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$, $\text{V}_{\text{ss}} = \text{EV}_{\text{ss}0} = \text{EV}_{\text{ss}1} = 0 \text{ V}$, Reference voltage (+) = AV_{REFP} , Reference voltage (-) = $\text{AV}_{\text{REFM}} = 0 \text{ V}$)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution $\text{EV}_{\text{DD}0} = \text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Notes 3, 4}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$		1.2	± 5.0	LSB
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 5}		1.2	± 8.5	LSB
Conversion time	t _{CONV}	10-bit resolution Target ANI pin : ANI16 to ANI26	3.6 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.125		39	μs
			2.7 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.1875		39	μs
			1.8 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
			1.6 V $\leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	57		95	μs
Zero-scale error ^{Notes 1, 2}	E _{ZS}	10-bit resolution $\text{EV}_{\text{DD}0} = \text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Notes 3, 4}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 0.35	%FSR
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 5}			± 0.60	%FSR
Full-scale error ^{Notes 1, 2}	E _{FS}	10-bit resolution $\text{EV}_{\text{DD}0} = \text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Notes 3, 4}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 0.35	%FSR
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 5}			± 0.60	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution $\text{EV}_{\text{DD}0} = \text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Notes 3, 4}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 3.5	LSB
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 5}			± 6.0	LSB
Differential linearity error ^{Note 1}	DLE	10-bit resolution $\text{EV}_{\text{DD}0} = \text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$ ^{Notes 3, 4}	1.8 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			± 2.0	LSB
			1.6 V $\leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$ ^{Note 5}			± 2.5	LSB
Analog input voltage	V _{AIN}	ANI16 to ANI26		0		AV_{REFP} and $\text{EV}_{\text{DD}0}$	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. When $\text{AV}_{\text{REFP}} < \text{V}_{\text{DD}}$, the MAX. values are as follows.

Overall error: Add ± 1.0 LSB to the MAX. value when $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$.

Zero-scale error/Full-scale error: Add $\pm 0.05\%$ FSR to the MAX. value when $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$.

Integral linearity error/ Differential linearity error: Add ± 0.5 LSB to the MAX. value when $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$.

4. When $\text{AV}_{\text{REFP}} < \text{EV}_{\text{DD}0} \leq \text{V}_{\text{DD}}$, the MAX. values are as follows.

Overall error: Add ± 4.0 LSB to the MAX. value when $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$.

Zero-scale error/Full-scale error: Add $\pm 0.20\%$ FSR to the MAX. value when $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$.

Integral linearity error/ Differential linearity error: Add ± 2.0 LSB to the MAX. value when $\text{AV}_{\text{REFP}} = \text{V}_{\text{DD}}$.

5. When the conversion time is set to 57 μs (min.) and 95 μs (max.).

- (4) When reference voltage (+) = Internal reference voltage ($\text{ADREFP1} = 1$, $\text{ADREFP0} = 0$), reference voltage (-) = $\text{AV}_{\text{REFM}}/\text{ANI1}$ ($\text{ADREFM} = 1$), target pin : ANI0, ANI2 to ANI14, ANI16 to ANI26

($T_A = -40$ to $+85^\circ\text{C}$, $2.4 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$, $1.6 \text{ V} \leq EV_{\text{DD0}} = EV_{\text{DD1}} \leq V_{\text{DD}}$, $V_{\text{SS}} = EV_{\text{SS0}} = EV_{\text{SS1}} = 0 \text{ V}$, Reference voltage (+) = $\text{VBGR}^{\text{Note 3}}$, Reference voltage (-) = $\text{AV}_{\text{REFM}} = 0 \text{ V}^{\text{Note 4}}$, HS (high-speed main) mode)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		bit	
Conversion time	tconv	8-bit resolution	$2.4 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	$2.4 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$			± 0.60	%FSR
Integral linearity error ^{Note 1}	ILE	8-bit resolution	$2.4 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$			± 2.0	LSB
Differential linearity error ^{Note 1}	DLE	8-bit resolution	$2.4 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$			± 1.0	LSB
Analog input voltage	V _{Ain}			0		$\text{VBGR}^{\text{Note 3}}$	V

Notes 1. Excludes quantization error ($\pm 1/2 \text{ LSB}$).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. Refer to **2.6.2 Temperature sensor/internal reference voltage characteristics**.

4. When reference voltage (-) = V_{SS} , the MAX. values are as follows.

Zero-scale error: Add $\pm 0.35\%$ FSR to the MAX. value when reference voltage (-) = AV_{REFM} .

Integral linearity error: Add $\pm 0.5 \text{ LSB}$ to the MAX. value when reference voltage (-) = AV_{REFM} .

Differential linearity error: Add $\pm 0.2 \text{ LSB}$ to the MAX. value when reference voltage (-) = AV_{REFM} .

LVD Detection Voltage of Interrupt & Reset Mode(T_A = -40 to +85°C, V_{PDR} ≤ V_{DD} ≤ 5.5 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit	
Interrupt and reset mode	V _{LVDA0}	V _{POC2} , V _{POC1} , V _{POC0} = 0, 0, 0, falling reset voltage	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.60	1.63	1.66	V
	V _{LVDA1}			Falling interrupt voltage	1.74	1.77	1.81	V
	V _{LVDA2}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.70	1.73	1.77	V
	V _{LVDA3}			Falling interrupt voltage	1.84	1.88	1.91	V
	V _{LVDB0}	V _{POC2} , V _{POC1} , V _{POC0} = 0, 0, 1, falling reset voltage	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
	V _{LVDB1}			Falling interrupt voltage	2.80	2.86	2.91	V
	V _{LVDB2}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.94	1.98	2.02	V
	V _{LVDB3}			Falling interrupt voltage	1.90	1.94	1.98	V
	V _{LVDC0}	V _{POC2} , V _{POC1} , V _{POC0} = 0, 1, 0, falling reset voltage	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V
	V _{LVDC1}			Falling interrupt voltage	2.00	2.04	2.08	V
	V _{LVDC2}		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	V
	V _{LVDC3}			Falling interrupt voltage	3.00	3.06	3.12	V
	V _{LVDD0}	V _{POC2} , V _{POC1} , V _{POC0} = 0, 1, 1, falling reset voltage	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.40	2.45	2.50	V
	V _{LVDD1}			Falling interrupt voltage	2.56	2.61	2.66	V
	V _{LVDD2}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.50	2.55	2.60	V
	V _{LVDD3}			Falling interrupt voltage	2.66	2.71	2.76	V
	V _{LVDD0}		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.60	2.65	2.70	V
	V _{LVDD1}			Falling interrupt voltage	3.68	3.75	3.82	V
	V _{LVDD2}		LVIS1, LVIS0 = 1, 1	Rising release reset voltage	3.60	3.67	3.74	V
	V _{LVDD3}			Falling interrupt voltage	2.96	3.02	3.08	V

(2) Flash ROM: 96 to 256 KB of 30- to 100-pin products

 $(T_A = -40$ to $+105^\circ\text{C}$, $2.4 \text{ V} \leq EV_{DD0} = EV_{DD1} \leq V_{DD} \leq 5.5 \text{ V}$, $V_{SS} = EV_{SS0} = EV_{SS1} = 0 \text{ V}$) (2/2)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current Note 1	I_{DD2} Note 2	HALT mode	HS (high-speed main) mode Note 7	$f_{IH} = 32 \text{ MHz}$ Note 4	$V_{DD} = 5.0 \text{ V}$		0.62	3.40	mA
					$V_{DD} = 3.0 \text{ V}$		0.62	3.40	mA
				$f_{IH} = 24 \text{ MHz}$ Note 4	$V_{DD} = 5.0 \text{ V}$		0.50	2.70	mA
					$V_{DD} = 3.0 \text{ V}$		0.50	2.70	mA
				$f_{IH} = 16 \text{ MHz}$ Note 4	$V_{DD} = 5.0 \text{ V}$		0.44	1.90	mA
					$V_{DD} = 3.0 \text{ V}$		0.44	1.90	mA
		HS (high-speed main) mode Note 7	$f_{MX} = 20 \text{ MHz}$ Note 3, $V_{DD} = 5.0 \text{ V}$	Square wave input		0.31	2.10	mA	
				Resonator connection		0.48	2.20	mA	
			$f_{MX} = 20 \text{ MHz}$ Note 3, $V_{DD} = 3.0 \text{ V}$	Square wave input		0.31	2.10	mA	
				Resonator connection		0.48	2.20	mA	
			$f_{MX} = 10 \text{ MHz}$ Note 3, $V_{DD} = 5.0 \text{ V}$	Square wave input		0.21	1.10	mA	
				Resonator connection		0.28	1.20	mA	
			$f_{MX} = 10 \text{ MHz}$ Note 3, $V_{DD} = 3.0 \text{ V}$	Square wave input		0.21	1.10	mA	
				Resonator connection		0.28	1.20	mA	
		Subsystem clock operation	$f_{SUB} = 32.768 \text{ kHz}$ Note 5 $T_A = -40^\circ\text{C}$	Square wave input		0.28	0.61	μA	
				Resonator connection		0.47	0.80	μA	
			$f_{SUB} = 32.768 \text{ kHz}$ Note 5 $T_A = +25^\circ\text{C}$	Square wave input		0.34	0.61	μA	
				Resonator connection		0.53	0.80	μA	
			$f_{SUB} = 32.768 \text{ kHz}$ Note 5 $T_A = +50^\circ\text{C}$	Square wave input		0.41	2.30	μA	
				Resonator connection		0.60	2.49	μA	
			$f_{SUB} = 32.768 \text{ kHz}$ Note 5 $T_A = +70^\circ\text{C}$	Square wave input		0.64	4.03	μA	
				Resonator connection		0.83	4.22	μA	
			$f_{SUB} = 32.768 \text{ kHz}$ Note 5 $T_A = +85^\circ\text{C}$	Square wave input		1.09	8.04	μA	
				Resonator connection		1.28	8.23	μA	
			$f_{SUB} = 32.768 \text{ kHz}$ Note 5 $T_A = +105^\circ\text{C}$	Square wave input		5.50	41.00	μA	
				Resonator connection		5.50	41.00	μA	
	I_{DD3} Note 6	STOP mode Note 8	$T_A = -40^\circ\text{C}$				0.19	0.52	μA
			$T_A = +25^\circ\text{C}$				0.25	0.52	μA
			$T_A = +50^\circ\text{C}$				0.32	2.21	μA
			$T_A = +70^\circ\text{C}$				0.55	3.94	μA
			$T_A = +85^\circ\text{C}$				1.00	7.95	μA
			$T_A = +105^\circ\text{C}$				5.00	40.00	μA

(Notes and Remarks are listed on the next page.)

(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (3/3)

(TA = -40 to +105°C, 2.4 V ≤ EV_{DD0} = EV_{DD1} ≤ V_{DD} ≤ 5.5 V, V_{ss} = EV_{SS0} = EV_{SS1} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
Slp setup time (to SCKp↓) ^{Note}	t _{SIK1}	4.0 V ≤ EV _{DD} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 30 pF, R _b = 1.4 kΩ	88		ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	88		ns
		2.4 V ≤ EV _{DD0} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 30 pF, R _b = 5.5 kΩ	220		ns
Slp hold time (from SCKp↓) ^{Note}	t _{KSI1}	4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 30 pF, R _b = 1.4 kΩ	38		ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	38		ns
		2.4 V ≤ EV _{DD0} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 30 pF, R _b = 5.5 kΩ	38		ns
Delay time from SCKp↑ to SO _p output ^{Note}	t _{KSO1}	4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 30 pF, R _b = 1.4 kΩ		50	ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ		50	ns
		2.4 V ≤ EV _{DD0} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 30 pF, R _b = 5.5 kΩ		50	ns

Note When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the Slp pin and the N-ch open drain output (V_{DD} tolerance (for the 20- to 52-pin products)/EV_{DD} tolerance (for the 64- to 100-pin products)) mode for the SO_p pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I²C mode) (1/2)(TA = -40 to +105°C, 2.4 V ≤ EV_{DD0} = EV_{DD1} ≤ V_{DD} ≤ 5.5 V, V_{SS} = EV_{SS0} = EV_{SS1} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCL _r clock frequency	f _{SCL}	4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 50 pF, R _b = 2.7 kΩ		400 ^{Note 1}	kHz
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ		400 ^{Note 1}	kHz
		4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 100 pF, R _b = 2.8 kΩ		100 ^{Note 1}	kHz
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ		100 ^{Note 1}	kHz
		2.4 V ≤ EV _{DD0} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 100 pF, R _b = 5.5 kΩ		100 ^{Note 1}	kHz
Hold time when SCL _r = "L"	t _{LOW}	4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 50 pF, R _b = 2.7 kΩ	1200		ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ	1200		ns
		4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 100 pF, R _b = 2.8 kΩ	4600		ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ	4600		ns
		2.4 V ≤ EV _{DD0} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 100 pF, R _b = 5.5 kΩ	4650		ns
Hold time when SCL _r = "H"	t _{HIGH}	4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 50 pF, R _b = 2.7 kΩ	620		ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ	500		ns
		4.0 V ≤ EV _{DD0} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 100 pF, R _b = 2.8 kΩ	2700		ns
		2.7 V ≤ EV _{DD0} < 4.0 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ	2400		ns
		2.4 V ≤ EV _{DD0} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 100 pF, R _b = 5.5 kΩ	1830		ns

(Notes and Caution are listed on the next page, and Remarks are listed on the page after the next page.)

3.6.5 Power supply voltage rising slope characteristics

($T_A = -40$ to $+105^\circ\text{C}$, $V_{SS} = 0$ V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	S_{VDD}				54	V/ms

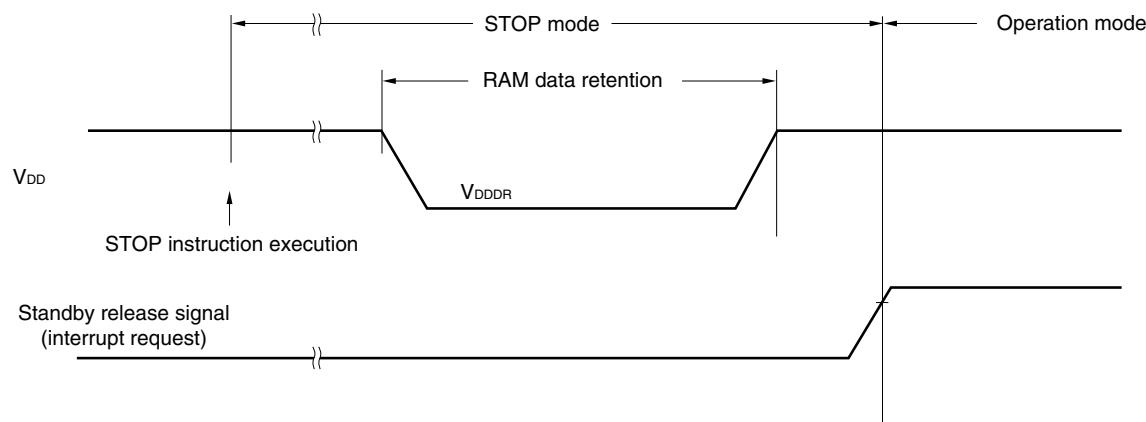
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V_{DD} reaches the operating voltage range shown in 3.4 AC Characteristics.

3.7 RAM Data Retention Characteristics

($T_A = -40$ to $+105^\circ\text{C}$, $V_{SS} = 0$ V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	V_{DDDR}		1.44 ^{Note}		5.5	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.

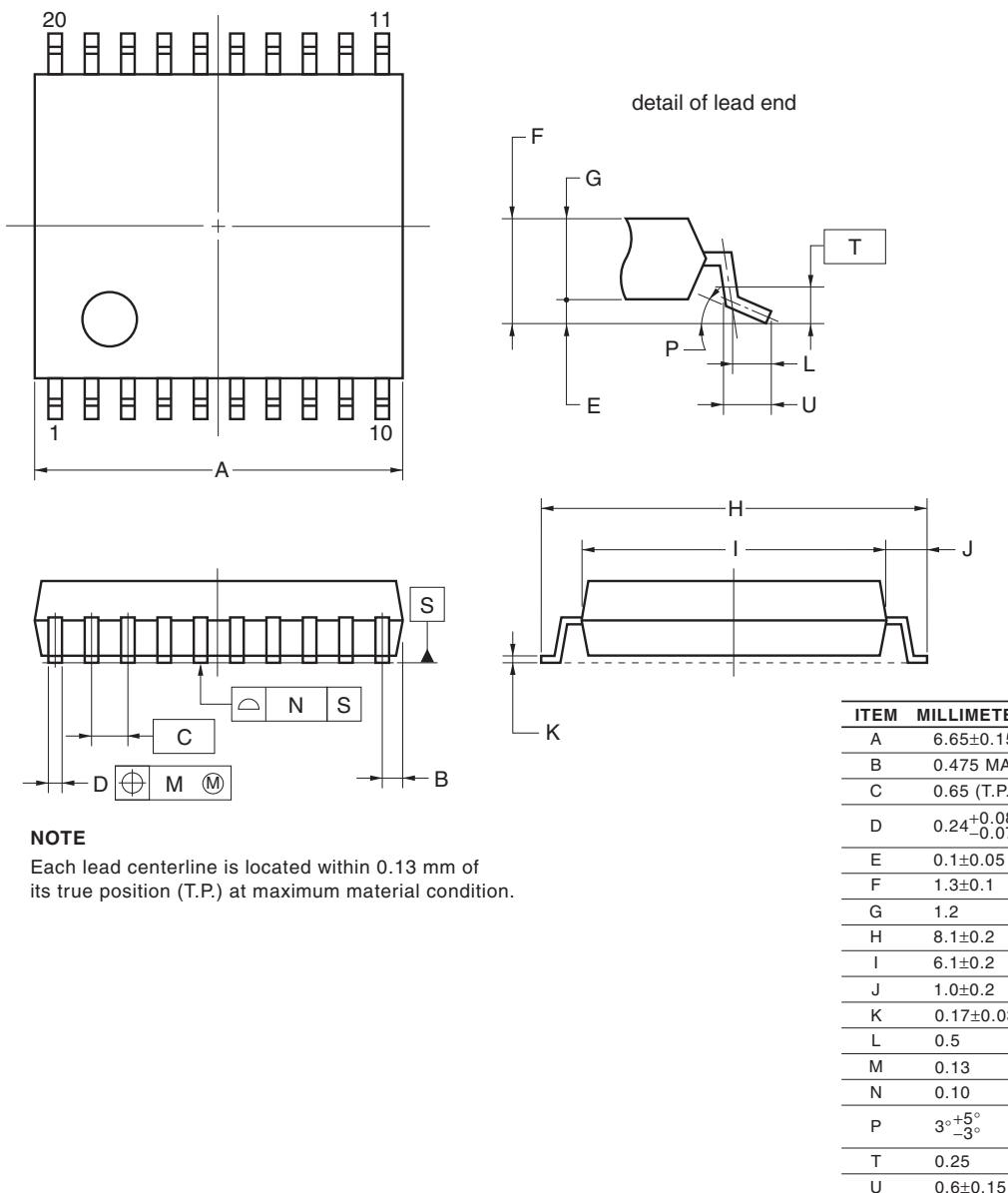


4. PACKAGE DRAWINGS

4.1 20-pin Products

R5F1006AASP, R5F1006CASP, R5F1006DASP, R5F1006EASP
 R5F1016AASP, R5F1016CASP, R5F1016DASP, R5F1016EASP
 R5F1006ADSP, R5F1006CDSP, R5F1006DDSP, R5F1006EDSP
 R5F1016ADSP, R5F1016CDSP, R5F1016DDSP, R5F1016EDSP
 R5F1006AGSP, R5F1006CGSP, R5F1006DGSP, R5F1006EGSP

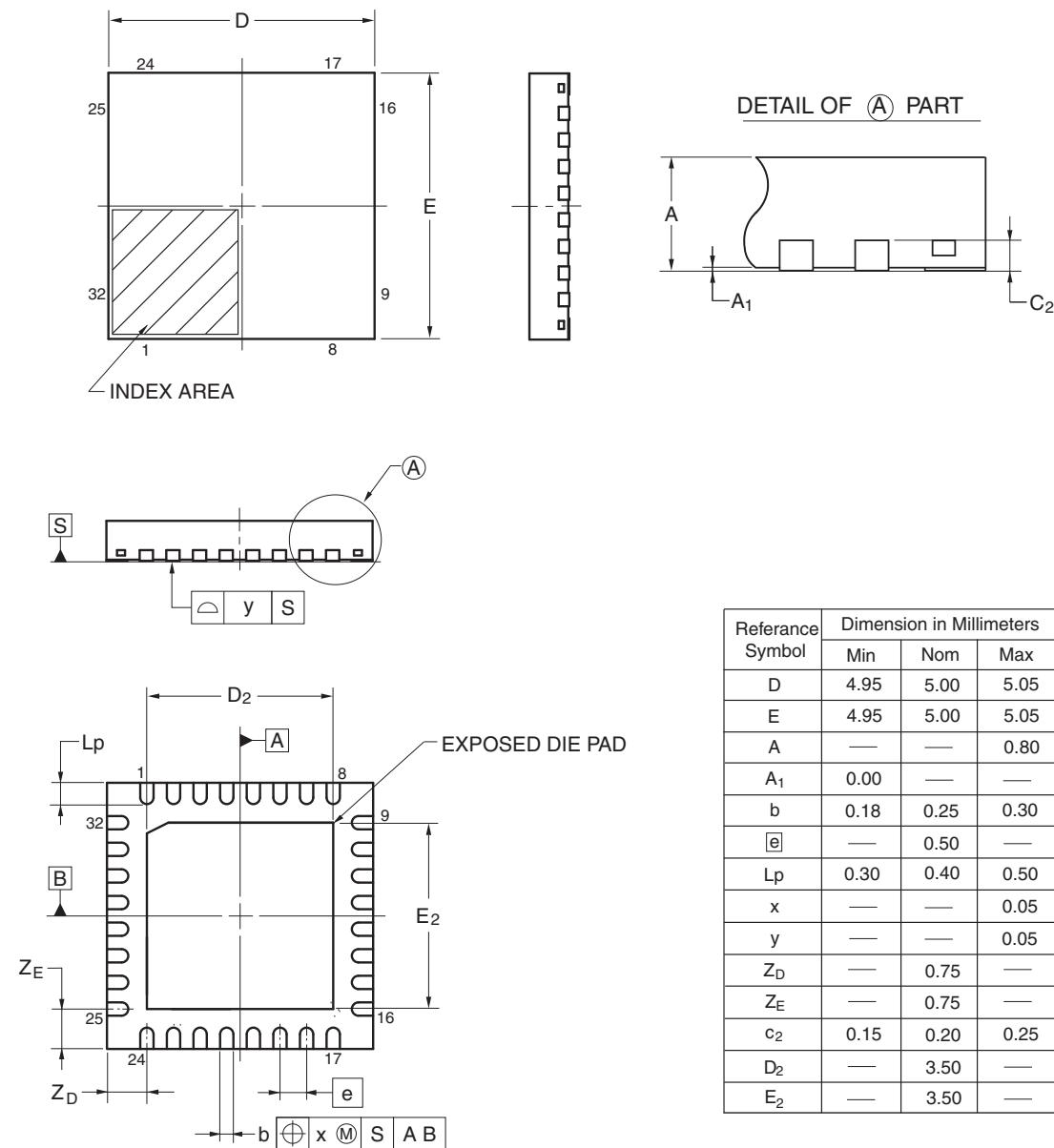
JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP20-0300-0.65	PLSP0020JC-A	S20MC-65-5A4-3	0.12



4.5 32-pin Products

R5F100BAANA, R5F100BCANA, R5F100BDANA, R5F100BEANA, R5F100BFANA, R5F100BGANA
 R5F101BAANA, R5F101BCANA, R5F101BDANA, R5F101BEANA, R5F101BFANA, R5F101BGANA
 R5F100BADNA, R5F100BCDNA, R5F100BDDNA, R5F100BEDNA, R5F100BFDNA, R5F100BGDNA
 R5F101BADNA, R5F101BCDNA, R5F101BDDNA, R5F101BEDNA, R5F101BFDNA, R5F101BGDNA
 R5F100BAGNA, R5F100BCGNA, R5F100BDGNA, R5F100BEGNA, R5F100BFGNA, R5F100BGGNA

JEITA Package code	RENESAS code	Previous code	MASS (TYP.)[g]
P-HWQFN32-5x5-0.50	PWQN0032KB-A	P32K8-50-3B4-5	0.06

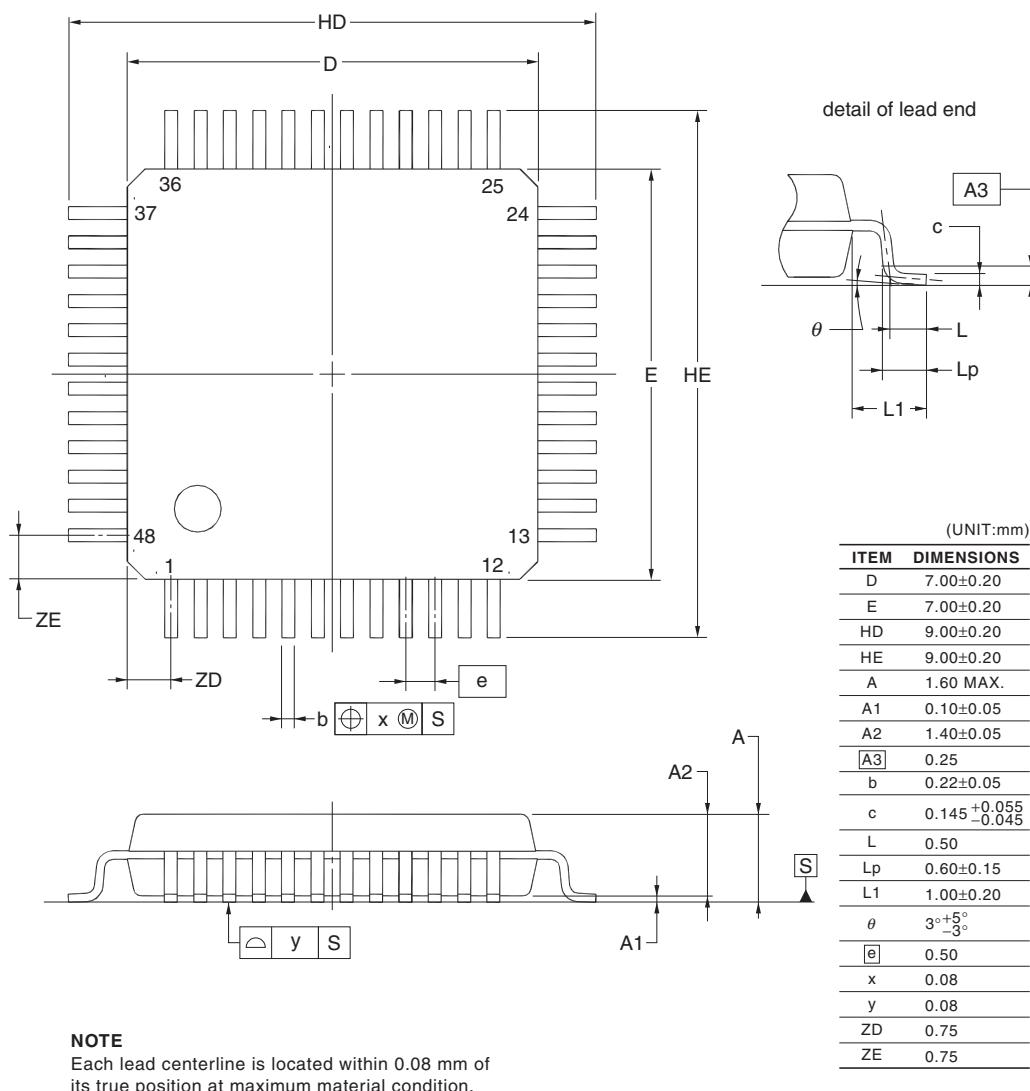


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4.9 48-pin Products

R5F100GAAFB, R5F100GCAFB, R5F100GDAFB, R5F100GEAFB, R5F100GFAFB, R5F100GGAFB,
 R5F100GHAFB, R5F100GJAFB, R5F100GKAFB, R5F100GLAFB
 R5F101GAAFB, R5F101GCAFB, R5F101GDAFB, R5F101GEAFB, R5F101GFAFB, R5F101GGAFB,
 R5F101GHAFB, R5F101GJAFB, R5F101GKAFB, R5F101GLAFB
 R5F100GADFB, R5F100GCDFB, R5F100GDDFB, R5F100GEDFB, R5F100GFDFB, R5F100GGDFB,
 R5F100GHDDB, R5F100GJDFB, R5F100GKDFB, R5F100GLDFB
 R5F101GADFB, R5F101GCDFB, R5F101GDDFB, R5F101GEDFB, R5F101GFDFB, R5F101GGDFB,
 R5F101GHDDB, R5F101GJDFB, R5F101GKDFB, R5F101GLDFB
 R5F100GAGFB, R5F100GCGFB, R5F100GDGFB, R5F100GEGFB, R5F100GFGFB, R5F100GGGFB,
 R5F100GHGFB, R5F100GJGFB

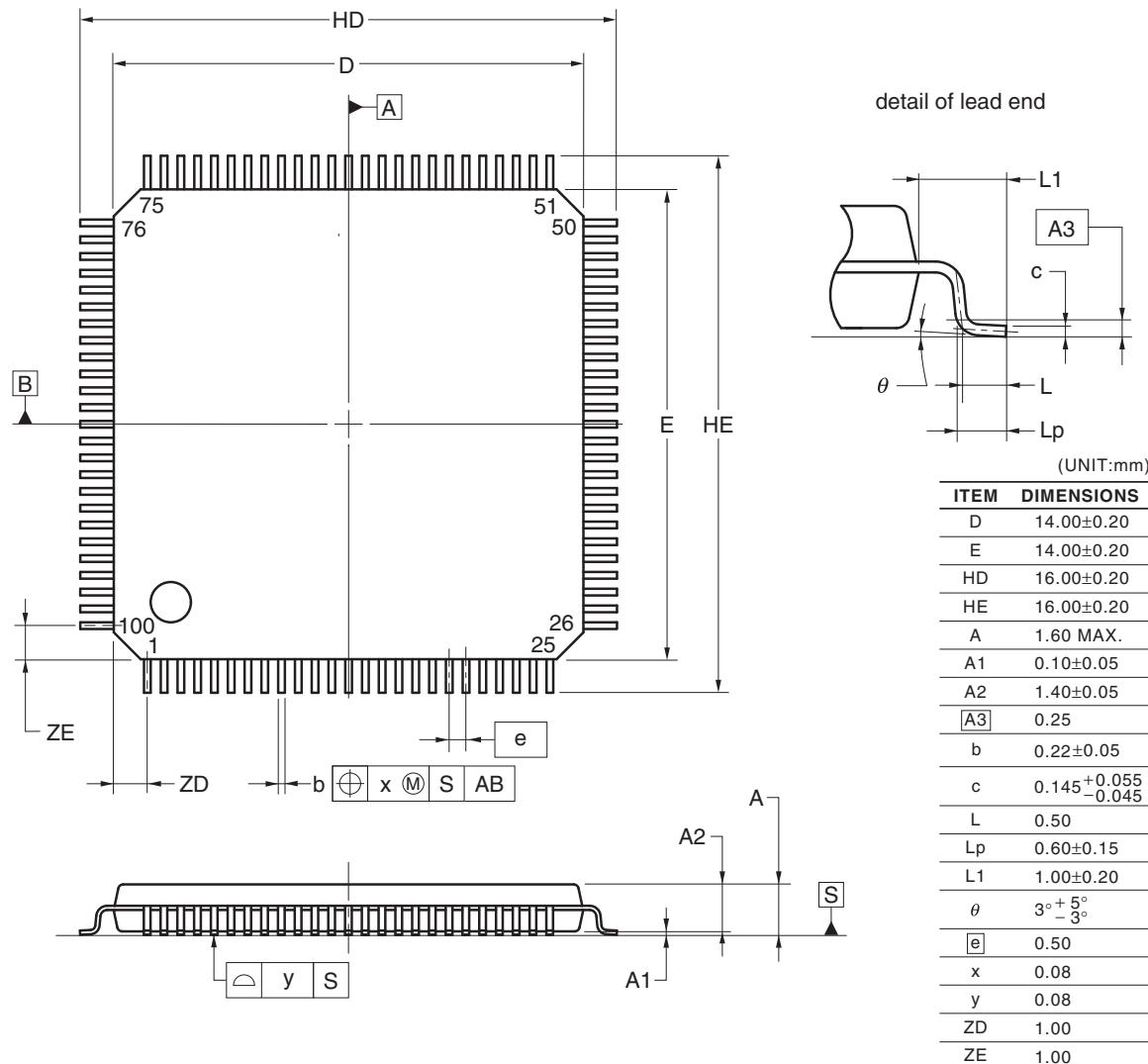
JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP48-7x7-0.50	PLQP0048KF-A	P48GA-50-8EU-1	0.16



4.13 100-pin Products

R5F100PFAFB, R5F100PGAFB, R5F100PHAFB, R5F100PJAFB, R5F100PKAFB, R5F100PLAFB
 R5F101PFAFB, R5F101PGAFB, R5F101PHAFB, R5F101PJAFB, R5F101PKAFB, R5F101PLAFB
 R5F100PFDFB, R5F100PGDFB, R5F100PHDFB, R5F100PJDFB, R5F100PKDFB, R5F100PLDFB
 R5F101PFDFB, R5F101PGDFB, R5F101PHDFB, R5F101PJDFB, R5F101PKDFB, R5F101PLDFB
 R5F100PFGFB, R5F100PGGFB, R5F100PHGFB, R5F100PJGFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP100-14x14-0.50	PLQP0100KE-A	P100GC-50-GBR-1	0.69



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Revision History		RL78/G13 Data Sheet	
Rev.	Date	Description	
		Page	Summary
1.00	Feb 29, 2012	-	First Edition issued
2.00	Oct 12, 2012	7	Figure 1-1. Part Number, Memory Size, and Package of RL78/G13: Pin count corrected.
		25	1.4 Pin Identification: Description of pins INTP0 to INTP11 corrected.
		40, 42, 44	1.6 Outline of Functions: Descriptions of Subsystem clock, Low-speed on-chip oscillator, and General-purpose register corrected.
		41, 43, 45	1.6 Outline of Functions: Lists of Descriptions changed.
		59, 63, 67	Descriptions of Note 8 in a table corrected.
		68	(4) Common to RL78/G13 all products: Descriptions of Notes corrected.
		69	2.4 AC Characteristics: Symbol of external system clock frequency corrected.
		96 to 98	2.6.1 A/D converter characteristics: Notes of overall error corrected.
		100	2.6.2 Temperature sensor characteristics: Parameter name corrected.
		104	2.8 Flash Memory Programming Characteristics: Incorrect descriptions corrected.
		116	3.10 52-pin products: Package drawings of 52-pin products corrected.
		120	3.12 80-pin products: Package drawings of 80-pin products corrected.
3.00	Aug 02, 2013	1	Modification of 1.1 Features
		3	Modification of 1.2 List of Part Numbers
		4 to 15	Modification of Table 1-1. List of Ordering Part Numbers, note, and caution
		16 to 32	Modification of package type in 1.3.1 to 1.3.14
		33	Modification of description in 1.4 Pin Identification
		48, 50, 52	Modification of caution, table, and note in 1.6 Outline of Functions
		55	Modification of description in table of Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$)
		57	Modification of table, note, caution, and remark in 2.2.1 X1, XT1 oscillator characteristics
		57	Modification of table in 2.2.2 On-chip oscillator characteristics
		58	Modification of note 3 of table (1/5) in 2.3.1 Pin characteristics
		59	Modification of note 3 of table (2/5) in 2.3.1 Pin characteristics
		63	Modification of table in (1) Flash ROM: 16 to 64 KB of 20- to 64-pin products
		64	Modification of notes 1 and 4 in (1) Flash ROM: 16 to 64 KB of 20- to 64-pin products
		65	Modification of table in (1) Flash ROM: 16 to 64 KB of 20- to 64-pin products
		66	Modification of notes 1, 5, and 6 in (1) Flash ROM: 16 to 64 KB of 20- to 64-pin products
		68	Modification of notes 1 and 4 in (2) Flash ROM: 96 to 256 KB of 30- to 100-pin products
		70	Modification of notes 1, 5, and 6 in (2) Flash ROM: 96 to 256 KB of 30- to 100-pin products
		72	Modification of notes 1 and 4 in (3) Flash ROM: 384 to 512 KB of 44- to 100-pin products
		74	Modification of notes 1, 5, and 6 in (3) Flash ROM: 384 to 512 KB of 44- to 100-pin products
		75	Modification of (4) Peripheral Functions (Common to all products)
		77	Modification of table in 2.4 AC Characteristics
		78, 79	Addition of Minimum Instruction Execution Time during Main System Clock Operation
		80	Modification of figures of AC Timing Test Points and External System Clock Timing